#### TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC7MZ240FK

Low Voltage Octal Bus Buffer (inverted) with 5 V Tolerant Inputs and Outputs

The TC7MZ240FK is a high performance CMOS octal bus buffer. Designed for use in 3.3 V systems, it achieves high speed operation while maintaining the CMOS low power dissipation.

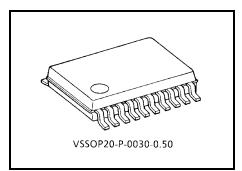
The device is designed for low-voltage  $(3.3 \text{ V}) \text{ V}_{CC}$  applications, but it could be used to interface to 5 V supply environment for both inputs and outputs.

The 7C7MZ240FK is an inverting 3-state buffer having two active-low output enables. This device is designed to be used with 3-state memory address drivers, etc.

All inputs are equipped with protection circuits against static discharge.

#### Features

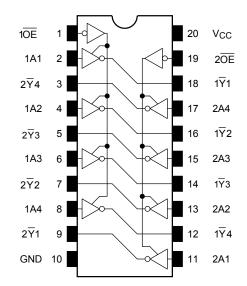
- Low voltage operation:  $V_{CC} = 2.0 \sim 3.6 \text{ V}$
- High speed operation:  $t_{pd} = 6.5 \text{ ns} (max) (V_{CC} = 3.0 \sim 3.6 \text{ V})$
- Output current:  $|I_{OH}|/I_{OL} = 24 \text{ mA} (min) (V_{CC} = 3.0 \text{ V})$
- Latch-up performance: -500 mA
- Package: VSSOP (US20)
- Power down protection is provided on all inputs and outputs.
- Pin and function compatible with the 74 series (74AC/VHC/HC/F/ALS/LS etc.) 240 type.



Weight: 0.03 g (typ.)

# <u>TOSHIBA</u>

#### Pin Assignment (top view)



#### **Truth Table**

Inp	uts	Outputs
ŌĒ	A <sub>n</sub>	Outputs
L	L	Н
L	Н	L
Н	Х	Z

X: Don't care

Z: High impedance

### Absolute Maximum Ratings (Note 1)

Characteristics	Symbol	Rating	Unit	
Supply voltage range	V <sub>CC</sub>	-0.5~7.0	V	
DC input voltage	VIN	-0.5~7.0	V	
DC output voltage	Vaur	-0.5~7.0 (Note 2)	V	
De ouiput voltage	Vout	-0.5~V <sub>CC</sub> + 0.5 (Note 3)		
Input diode current	I <sub>IK</sub>	-50	mA	
Output diode current	Іок	±50 (Note 4)	mA	
DC output current	lout	±50	mA	
Power dissipation	PD	180	mW	
DC V <sub>CC</sub> /ground current	I <sub>CC</sub> /I <sub>GND</sub>	±100	mA	
Storage temperature	T <sub>stg</sub>	-65~150	°C	

Note 1: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

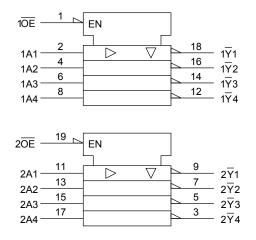
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note 2: Output in off-state

Note 3: High or low state. I<sub>OUT</sub> absolute maximum rating must be observed.

Note 4:  $V_{OUT} < GND, V_{OUT} > V_{CC}$ 

# IEC Logic Symbol



# **Operating Ranges (Note 1)**

Characteristics	Symbol	Rating	Unit
Supply voltage	V <sub>CC</sub>	2.0~3.6	
Supply vollage	VCC	1.5~3.6 (Note 2)	V
Input voltage	V <sub>IN</sub>	0~5.5	V
Output voltage	Vout	0~5.5 (Note 3)	v
Output voltage	V001	0~V <sub>CC</sub> (Note 4)	
Output current	Іон/Іог	±24 (Note 5)	mA
Output current	IOH/IOL	±12 (Note 6)	IIIA
Operating temperature	T <sub>opr</sub>	-40~85	°C
Input rise and fall time	dt/dv	0~10 (Note 7)	ns/V

Note 1: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either VCC or GND.

Note 2: Data retention only

Note 3: Output in off-state

Note 4: High or low state

Note 5: V<sub>CC</sub> = 3.0~3.6 V

Note 6:  $V_{CC} = 2.7 \sim 3.0 \text{ V}$ 

Note 7:  $V_{IN} = 0.8 \text{--} 2.0 \text{ V}, \text{ V}_{CC} = 3.0 \text{ V}$ 

# **Electrical Characteristics**

#### DC Characteristics ( $Ta = -40 \sim 85^{\circ}C$ )

Characte	eristics	Symbol	Test Condition		Min	Max	Unit	
		- ,			$V_{CC}(V)$		Max	onic
Input voltage	High level	VIH		_	2.7~3.6	2.0	—	v
input voltage	Low level	V <sub>IL</sub>		—	2.7~3.6	_	0.8	v
				I <sub>OH</sub> = -100 μA	2.7~3.6	V <sub>CC</sub> - 0.2		v
	High level	V <sub>OH</sub>	$V_{IN} = V_{IH} \text{ or } V_{IL}$	$I_{OH} = -12 \text{ mA}$	2.7	2.2	_	
				I <sub>OH</sub> = -18 mA	3.0	2.4	_	
Output voltage				$I_{OH} = -24 \text{ mA}$	3.0	2.2	_	
				I <sub>OL</sub> = 100 μA	2.7~3.6	_	0.2	
	Max		$I_{OL} = 12 \text{ mA}$	2.7	_	0.4		
	Low level V <sub>OL</sub>	VOL	$V_{IN} = V_{IH} \text{ or } V_{IL}$	I <sub>OL</sub> = 16 mA	3.0	_	0.4	
				$I_{OL} = 24 \text{ mA}$	3.0	_	0.55	
Input leakage cu	irrent	lin	V <sub>IN</sub> = 0~5.5 V		2.7~3.6	_	±5.0	μA
2 state output of			$V_{IN} = V_{IH} \text{ or } V_{IL}$		2.7~3.6		±5.0	μΑ
3-state output off-state current I <sub>OZ</sub>		loz	V <sub>OUT</sub> = 0~5.5 V		2.7~3.0			
Power off leakag	je current	IOFF	$V_{IN}/V_{OUT} = 5.5 V   0$		0	_	10.0	μA
Quiescent supply current			$V_{IN} = V_{CC} \text{ or } GND$		2.7~3.6	_	10.0	
Quiescent suppl	uiescent supply current I <sub>CC</sub>		$V_{IN}/V_{OUT} = 3.6 \sim 5.5 V$		2.7~3.6	_	±10.0	μA
Increase in ICC p	per input	∆lcc	$V_{IH} = V_{CC} - 0.6 V$		2.7~3.6		500	

### AC Characteristics (Ta = -40~85°C)

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Min	Max	Unit
Propagation delay time	t <sub>pLH</sub>	Figure 1, Figure 2	2.7	_	7.5	ns
Tropagation delay time	t <sub>pHL</sub>		$\textbf{3.3}\pm\textbf{0.3}$	1.5	6.5	113
Output enable time	t <sub>pZL</sub>	Figure 1, Figure 3	2.7	—	9.0	ns
	t <sub>pZH</sub>		$\textbf{3.3}\pm\textbf{0.3}$	1.5	8.0	
Output disable time	t <sub>pLZ</sub>		2.7	_	8.0	ns
	t <sub>pHZ</sub>	Figure 1, Figure 3	$\textbf{3.3}\pm\textbf{0.3}$	1.5	7.0	115
	t <sub>osLH</sub>	(81-4-)	2.7	_	_	ns
Output to output skew	t <sub>osHL</sub>	(Note)	$\textbf{3.3}\pm\textbf{0.3}$	_	1.0	115

Note: This parameter is guaranteed by design.

 $(t_{osLH} = |t_{pLHm} - t_{pLHn}|, t_{osHL} = |t_{pHLm} - t_{pHLn}|)$ 

#### Dynamic Switching Characteristics (Ta = 25°C, Input: $t_r = t_f = 2.5$ ns, $C_L = 50$ pF, $R_L = 500 \Omega$ )

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Тур.	Unit
Quiet output maximum dynamic VOL	V <sub>OLP</sub>	$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$	3.3	0.8	V
Quiet output minimum dynamic VOL	V <sub>OLV</sub>	$V_{IH} = 3.3 \text{ V}, V_{IL} = 0 \text{ V}$	3.3	0.8	V

# **Capacitive Characteristics (Ta = 25°C)**

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Тур.	Unit
Input capacitance	CIN	_	3.3	7	pF
Output capacitance	C <sub>OUT</sub>	_	3.3	8	pF
Power dissipation capacitance	C <sub>PD</sub>	f <sub>IN</sub> = 10 MHz (Note)	3.3	25	pF

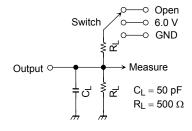
Note: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption.

Average operating current can be obtained by the equation:

 $I_{CC (opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/8$  (per bit)

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# **AC Test Circuit**



Parameter	Switch
t <sub>pLH</sub> , t <sub>pHL</sub>	Open
tpLZ, tpZL	6.0 V
t <sub>pHZ</sub> , t <sub>pZH</sub>	GND

Figure 1

# **AC Waveform**

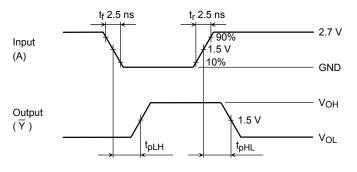


Figure 2 t<sub>pLH</sub>, t<sub>pHL</sub>

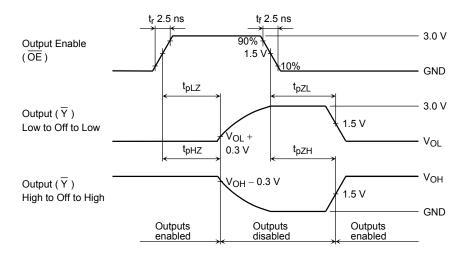
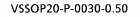
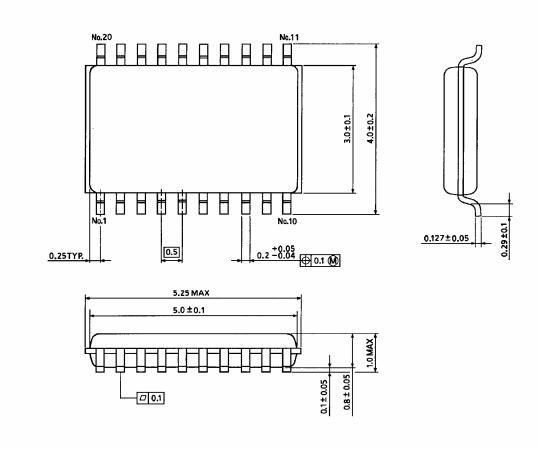


Figure 3  $t_{pLZ}, t_{pHZ}, t_{pZL}, t_{pZH}$ 

# Package Dimensions



Unit : mm



Weight: 0.03 g (typ.)

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20070701-EN GENERAL

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